

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1748		SERIAL NO. 09/879,231	
LIST OF ARTS CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Garo J. Derderian			
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
TL	AA	6,482,740	11/02	Soininen et al			
	AB	5,908,947	06/99	Vaartstra			
	AC	6,403,156	06/02	Jang			
	AD	6,746,930	06/04	Yang			
	AE	2002/0142488	10/02	Hong, Suk-Kyoung			
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	AL						

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AM							
AN							
AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
TL	AP	Suntola, "Surface Chemistry of Materials Deposition at Atomic Layer Level," Applied Surface Science, vol. 100/101, March 1996, pp. 391-398.
TL	AQ	T. Suntola, Atomic Layer Epitaxy, Handbook of Crystal Growth, Vol. 3, 1994, pp. 603-663.
TL	AR	Leskela and Ritala, ALD Precursor Chemistry: Evolution and Future Challenges, J. Phys. IV France 9 (1999), pages 837-852.
TL	AS	Ritala et al, "Perfectly Conformal TiN and Al ₂ O ₃ Films Deposited by Atomic Layer Deposition," Chemical Vapor Deposition, v. 5, No. 1, 1999, pp. 7-9.

EXAMINER <i>[Signature]</i>	DATE CONSIDERED 04/02/05
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/	AA	09/653,156	Agarwal (as amended 8/12/02, 2/18/03, 10/13/03, 3/30/04, 12/27/04)			08/2000
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	AG					
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	AI					
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FOREIGN PATENT DOCUMENTS							
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